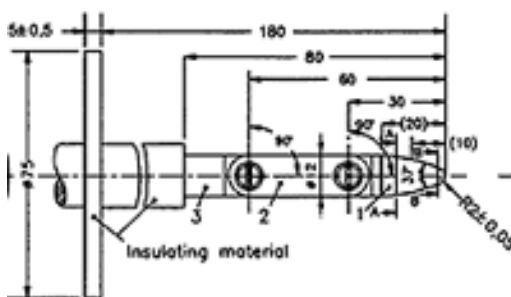


Jointed IEC Finger Probe

Model TFP-01

The Jointed Finger Probe is a high-precision probe made in exact accordance with IEC standards such as IEC 60950, IEC 61010, and IEC 61032 and is also used for CSA and UL standards. It features a palm simulator to prevent misuse, and a restricted joint movement which simulates human finger movement. The finger is made of chrome-plated steel and the rest of the instrument is Delrin®.



The handle incorporates a banana jack in order to check the continuity - as required by the Standards.

All ED&D probes come with NIST traceable certificates of calibration. Calibration Measurement Data is also available at an additional charge.

OPTIONAL ACCESSORIES:

Electrical Contact Indicator Model LVI-01



Unit is required in many standards, used to determine if probe is able to make electrical contact within product under test. Test Finger must be purchased separately.

With transformer 230V / 42V 25mA 50-60 Hz,
With pilot lamp 36-45V / 2W, with 2 connecting leads and with 2 tapping clips
According to IEC 60529, IEC 60598, EN 60335 and others

Other Voltages, Etc. available by request